

## **Power MOSFET**

PRODUCT SUMMARY				
V <sub>DS</sub> (V)	850			
R <sub>DS(on)</sub> (Ω)	V <sub>GS</sub> = 10 V 1.2			
Q <sub>g</sub> (Max.) (nC)	200			
Q <sub>gs</sub> (nC)	24			
Q <sub>gd</sub> (nC)	110			
Configuration	Single			

#### **FEATURES**

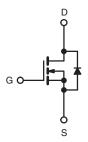
- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Isolated Central Mounting Hole
- Fast Switching
- Ease of Paralleling
- Simple Drive Requirements
- Compliant to RoHS Directive 2002/95/EC





#### D<sup>2</sup>PAK (TO-263)





N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS (T <sub>C</sub>	= 25 °C, unless otherwis	se noted)		
PARAMETER	SYMBOL	LIMIT	UNIT	
Drain-Source Voltage	$V_{DS}$	850	V	
Gate-Source Voltage		$V_{GS}$	± 20	v
Continuous Drain Current	$V_{GS}$ at 10 V $T_{C} = 25 ^{\circ}\text{C}$ $T_{C} = 100 ^{\circ}\text{C}$	I <sub>D</sub>	7.0	
Continuous Drain Current	$T_C = 100 ^{\circ}C$		5.2	Α
Pulsed Drain Current <sup>a</sup>		I <sub>DM</sub>	20	
Linear Derating Factor		1.5	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>	E <sub>AS</sub>	880	mJ	
Repetitive Avalanche Current <sup>a</sup>	I <sub>AR</sub>	8.7	Α	
Repetitive Avalanche Energy <sup>a</sup>	E <sub>AR</sub>	19	mJ	
Maximum Power Dissipation	$P_{D}$	190	W	
Peak Diode Recovery dV/dt <sup>c</sup>	dV/dt	1.5	V/ns	
Operating Junction and Storage Temperature Rang	T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 150	°C	
Soldering Recommendations (Peak Temperature)		300 <sup>d</sup>		
Mounting Torque	6-32 or M3 screw		10	lbf ⋅ in
Mounting Torque	0-32 OF IVIS SCIEW		1.1	N⋅m

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b.  $V_{DD} = 50 \text{ V}$ , starting  $T_J = 25 \,^{\circ}\text{C}$ ,  $L = 37 \,\text{mH}$ ,  $R_g = 25 \,^{\circ}\Omega$ ,  $I_{AS} = 6.7 \,\text{A}$  (see fig. 12). c.  $I_{SD} \le 6.7 \,^{\circ}\Lambda$ ,  $I_{AS} = 6.7 \,^{\circ}\Lambda$
- d. 1.6 mm from case.

<sup>\*</sup> Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	$R_{thJA}$	-	40		
Case-to-Sink, Flat, Greased Surface	R <sub>thCS</sub>	0.24	-	°C/W	
Maximum Junction-to-Case (Drain)	$R_{thJC}$	-	0.65		

PARAMETER	SYMBOL	TEST	TEST CONDITIONS		TYP.	MAX.	UNIT	
Static								
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0$	V, I <sub>D</sub> = 250 μA	850	-	-	V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference t	to 25 °C, I <sub>D</sub> = 1 mA	-	1.2	-	V/°C	
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V$	<sub>GS</sub> , I <sub>D</sub> = 250 μA	2.0	-	4.0	V	
Gate-Source Leakage	I <sub>GSS</sub>	V <sub>G</sub>	<sub>S</sub> = ± 20 V	-	-	± 100	nA	
Zone Ooto Waltana Dunin Orumant		V <sub>DS</sub> = 88	V <sub>DS</sub> = 850 V, V <sub>GS</sub> = 0 V		-	100		
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = 760 V, V	/ <sub>GS</sub> = 0 V, T <sub>J</sub> = 125 °C	-	-	500	μA	
Drain-Source On-State Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 4.0 A <sup>b</sup>	-	1.2	-	Ω	
Forward Transconductance	9 <sub>fs</sub>	V <sub>DS</sub> = 10	00 V, I <sub>D</sub> = 4.0 A <sup>b</sup>	4.9	-	-	S	
Dynamic								
Input Capacitance	C <sub>iss</sub>	V	<sub>GS</sub> = 0 V,	-	2900	-	pF	
Output Capacitance	C <sub>oss</sub>	V	os = 25 V,	-	270	-		
Reverse Transfer Capacitance	C <sub>rss</sub>	f = 1.0 l	MHz, see fig. 5	-	92	-		
Total Gate Charge	Qg				-	200		
Gate-Source Charge	$Q_{gs}$	V <sub>GS</sub> = 10 V	$I_D = 6.7 \text{ A}, V_{DS} = 360 \text{ V},$ see fig. 6 and 13 <sup>b</sup>	-	-	24	nC	
Gate-Drain Charge	Q <sub>gd</sub>		l see lig. c al.a re	-	-	110		
Turn-On Delay Time	t <sub>d(on)</sub>		'		20	-	- ns	
Rise Time	t <sub>r</sub>	$V_{DD} = 475 \text{ V}, I_D = 6.7 \text{ A},$ $R_G = 6.2 \Omega, R_D = 67 \Omega, \text{ see fig. } 10^b$		-	34	-		
Turn-Off Delay Time	t <sub>d(off)</sub>			-	130	-		
Fall Time	t <sub>f</sub>			-	37	-		
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") fro	Between lead, 6 mm (0.25") from		5.0	-		
Internal Source Inductance	L <sub>S</sub>	package and center of die contact		-	13	-	- nH	
Drain-Source Body Diode Characteristic	s							
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbo	MOSFET symbol showing the		-	7	A	
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>	integral reverse p - n junction diode		-	-	1 8		
Body Diode Voltage	$V_{SD}$	T <sub>J</sub> = 25 °C, I <sub>S</sub>	T <sub>J</sub> = 25 °C, I <sub>S</sub> = 6.7 A, V <sub>GS</sub> = 0 V <sup>b</sup>		-	1.8	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>	T 25 °C 1			610	920	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	$T_J = 25  ^{\circ}\text{C}, I_F = 6.7  \text{A}, dI/dt = 100  \text{A}/\mu\text{s}^{\text{b}}$		-	3.2	4.8	μC	
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on			Intrinsic turn-on time is negligible (turn-on is dominated by $L_S$ and $L_D$ )			L <sub>D</sub> )

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width  $\leq$  300 µs; duty cycle  $\leq$  2 %.



### TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

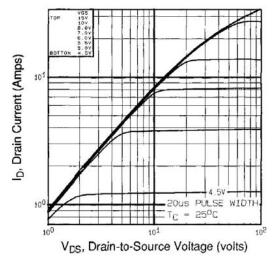


Fig. 1 - Typical Output Characteristics, T<sub>C</sub> = 25 °C

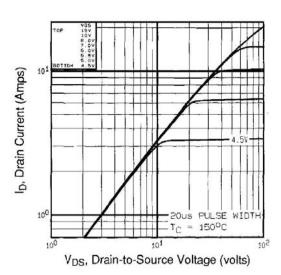


Fig. 2 - Typical Output Characteristics,  $T_C = 150$  °C

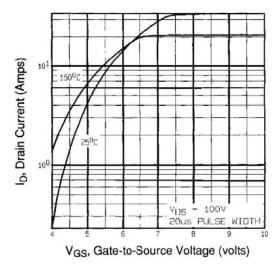


Fig. 3 - Typical Transfer Characteristics

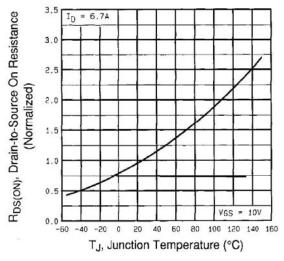


Fig. 4 - Normalized On-Resistance vs. Temperature



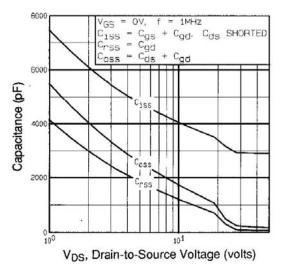


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

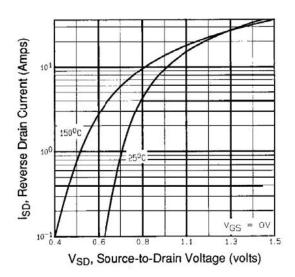


Fig. 7 - Typical Source-Drain Diode Forward Voltage

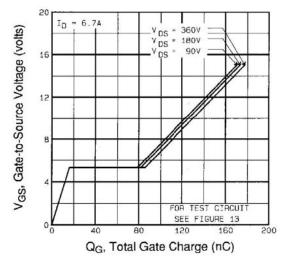


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

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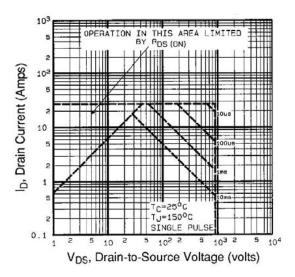


Fig. 8 - Maximum Safe Operating Area



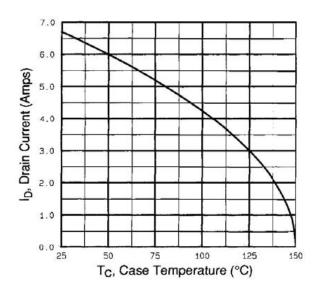


Fig. 9 - Maximum Drain Current vs. Case Temperature

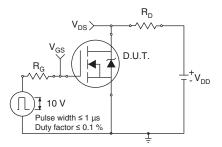


Fig. 10a - Switching Time Test Circuit

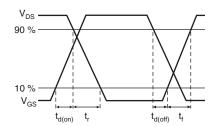


Fig. 10b - Switching Time Waveforms

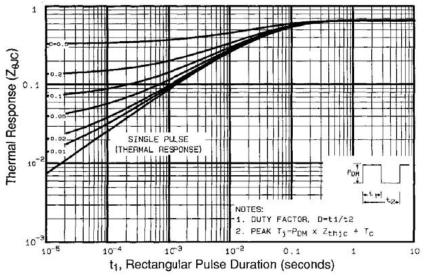


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

服务热线:400-655-8788 5



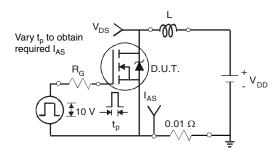


Fig. 12a - Unclamped Inductive Test Circuit

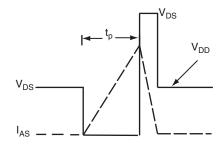


Fig. 12b - Unclamped Inductive Waveforms

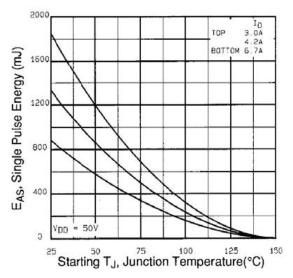


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

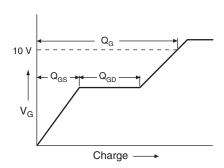


Fig. 13a - Basic Gate Charge Waveform

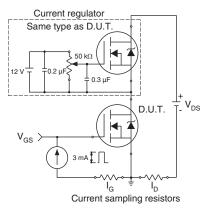
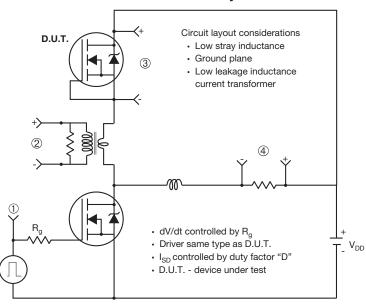


Fig. 13b - Gate Charge Test Circuit



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#### Peak Diode Recovery dV/dt Test Circuit



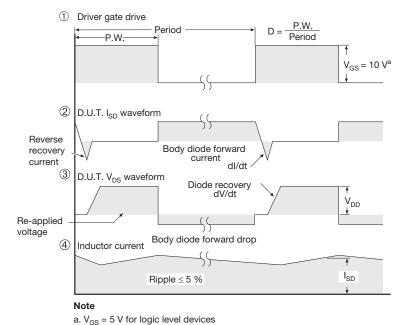
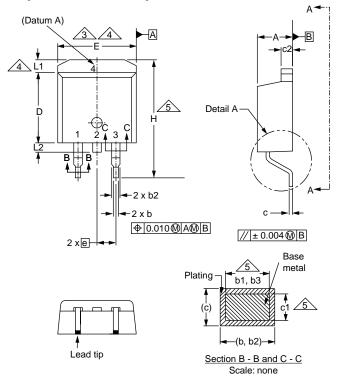
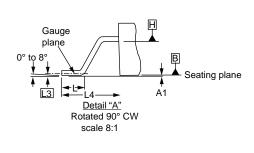


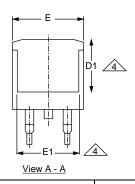
Fig. 14 - For N-Channel



#### **TO-263AB (HIGH VOLTAGE)**







	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
Α	4.06	4.83	0.160	0.190
A1	0.00	0.25	0.000	0.010
b	0.51	0.99	0.020	0.039
b1	0.51	0.89	0.020	0.035
b2	1.14	1.78	0.045	0.070
b3	1.14	1.73	0.045	0.068
С	0.38	0.74	0.015	0.029
c1	0.38	0.58	0.015	0.023
c2	1.14	1.65	0.045	0.065
D	8.38	9.65	0.330	0.380

	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
D1	6.86	-	0.270	-
Е	9.65	10.67	0.380	0.420
E1	6.22	-	0.245	-
е	2.54 BSC		0.100 BSC	
Н	14.61	15.88	0.575	0.625
L	1.78	2.79	0.070	0.110
L1	-	1.65	-	0.066
L2	-	1.78	-	0.070
L3	0.25 BSC		0.010	BSC
L4	4.78	5.28	0.188	0.208

DWG: 5970

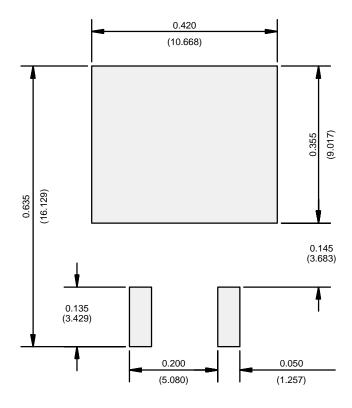
ECN: S-82110-Rev. A, 15-Sep-08

#### Notes

- 1. Dimensioning and tolerancing per ASME Y14.5M-1994.
- 2. Dimensions are shown in millimeters (inches).
- 3. Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm (0.005") per side. These dimensions are measured at the outmost extremes of the plastic body at datum A.
- 4. Thermal PAD contour optional within dimension E, L1, D1 and E1.
- 5. Dimension b1 and c1 apply to base metal only.
- 6. Datum A and B to be determined at datum plane H.
- 7. Outline conforms to JEDEC outline to TO-263AB.



### RECOMMENDED MINIMUM PADS FOR D<sup>2</sup>PAK: 3-Lead



Recommended Minimum Pads Dimensions in Inches/(mm)



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